

Crystal oscillator

SMD CMOS Output 3.2×2.5×1.0mm 3N Series



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SPECIFICATION

PN: SJK-3NA0000M1H0420K2

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FEATURE

- Ultra Small SMD seam sealed clock crystal oscillator units.
- For applications in WLAN, Bluetooth, DSC, DSL and other IT product.
- Tri-state function available.
- RoHS Compliant / Pb Free.

ELECTRICAL SPECIFICATIONS (电气参数)

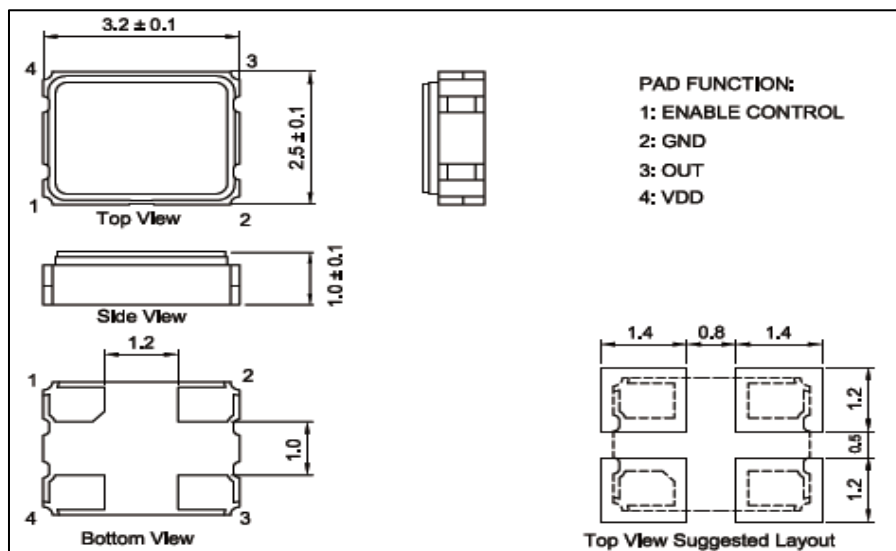
Parmeters	Condition\Model	3N
Fan Out Type		CMOS
Supply Voltage		1.8V±10%
Frequency		100.000MHz
Operating Temperature		-40℃ to +85℃
Current		20mA max
Frequency Stability	All Conditions	±20ppm
Output Voltage	Vol(max)	10%VDD
	VoH(min)	90%VDD
Rise/Fall Time	AT 0.1Vdd~0.9Vdd	5ns max
Load Capacitance		15pF
Duty Cycle		50±10%
Storage Temperature		-55~+125℃
Start-upTime	Load RANGE	5mSec max
Aging		±3ppm(1st ,year at 25℃)
Tri-State	Output Active	2.31V Min Pin 1 Tri-state
	Output in High-Impedance	0.99V Max
PAD Connection	PIN#1 Tri-State/NC	PIN#3 OUT
	PIN#2 GND	PIN#4 Vdd

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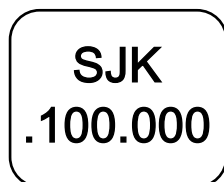
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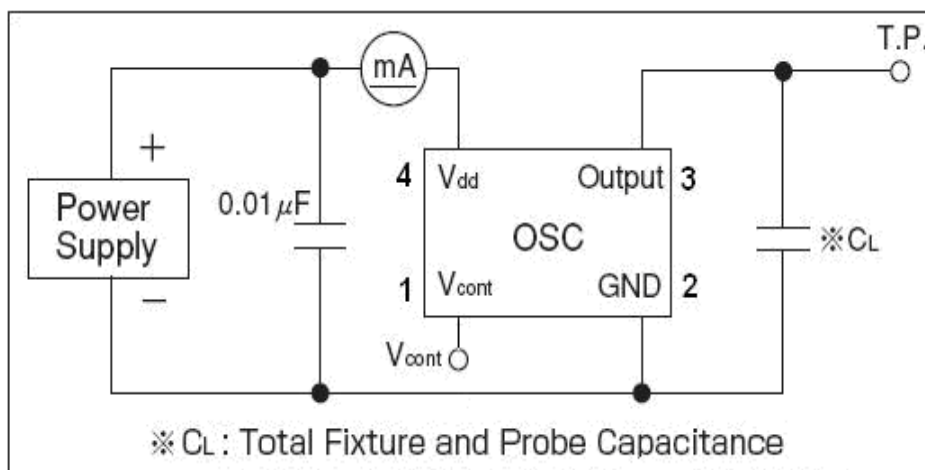
Dimension (尺寸) (Unit: mm)



MARK (印字)



MEASUREMENT CIRCUIT (电路)

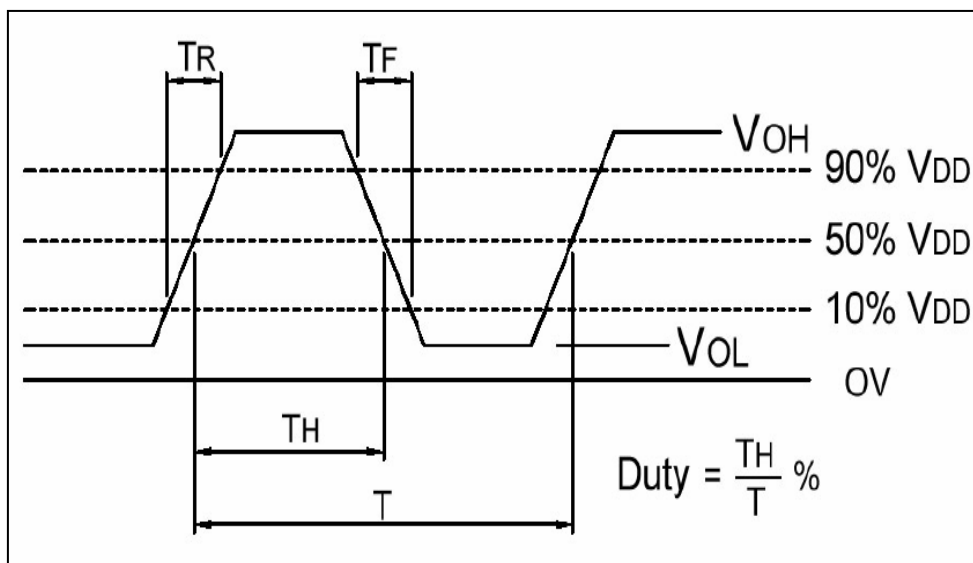


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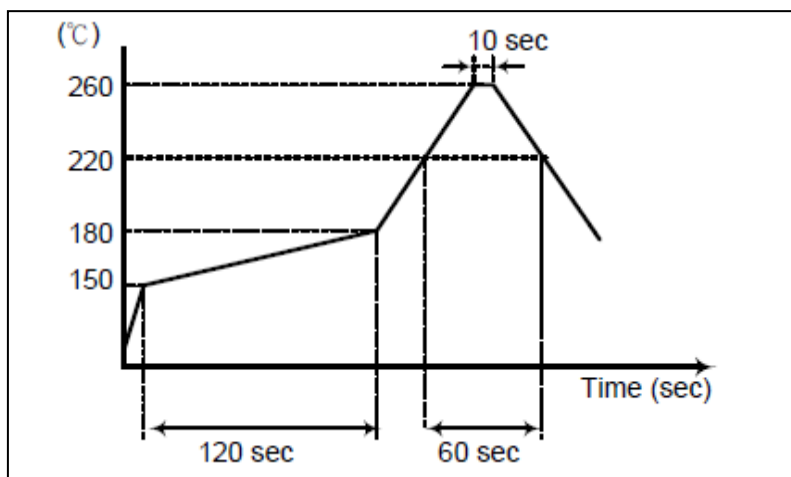
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WAVEFORM CONDITIONS (波形)



REFLOW CONDITION (回流焊)



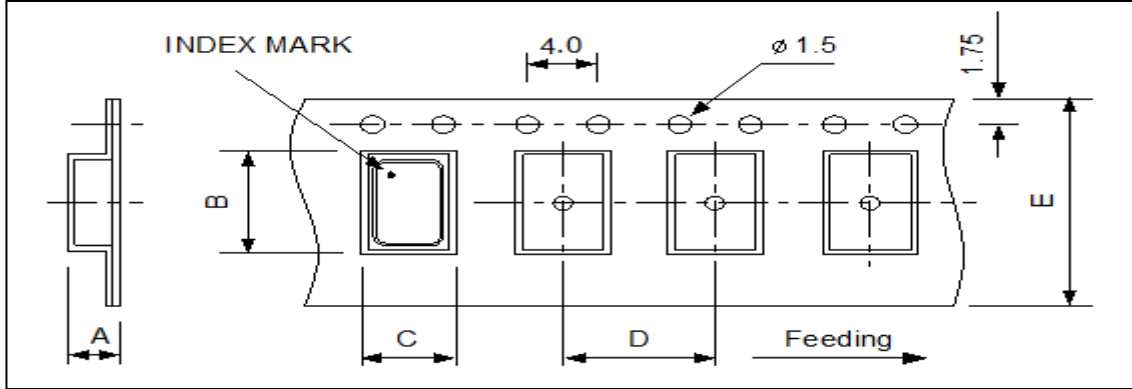
The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details

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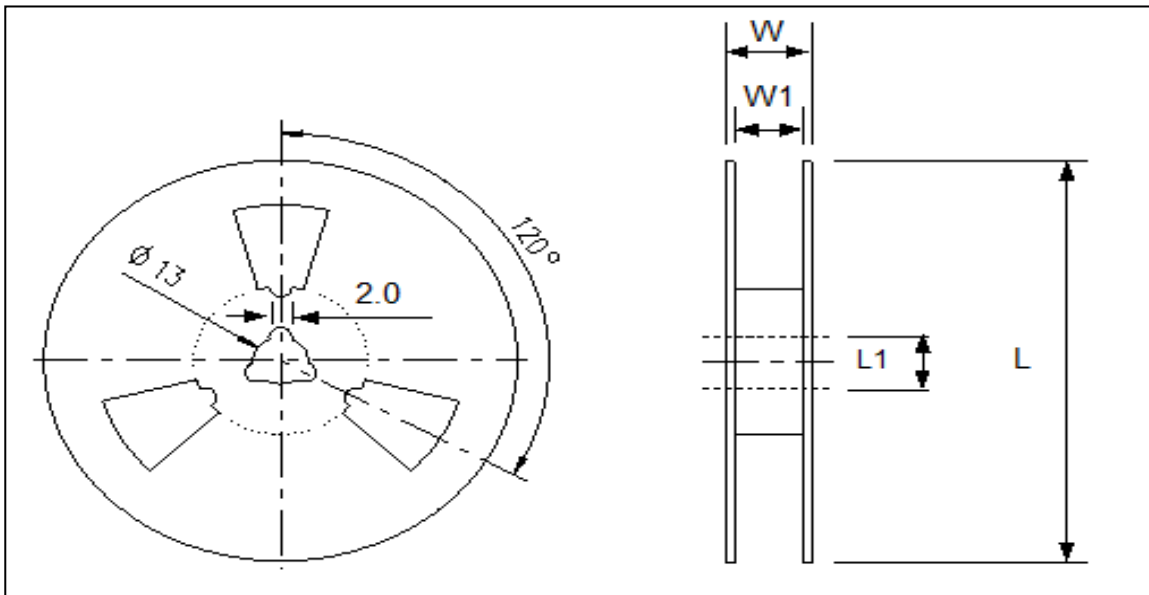
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CARRIER TYPE (載帶)



REEL(卷盘)



DIMENSIONS		A	B	C	D	E	L	L1	W	W1	pcs / Reel
	7050	2.15	7.9	5.4	8	16	180	13	21.5	17.5	1K
	6035	1.4	6.4	3.9	8	12	180	13	15.4	13	1K
	5032	1.46	5.5	3.6	8	12	180	13	15.4	13	1K
	3225	1.4	3.4	2.7	4	8	180	13	11.5	8	3K
	2520	1.15	2.8	2.25	4	8	180	13	10.5	8	3K
	2016	0.95	2.25	2.25	4	8	180	13	10.5	9	3K
	1612	0.8	2.0	1.85	4	8	180	13	10.5	9	3K

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RELIABILITY TEST SPECIFICATIONS (可靠性测试标准)

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	1.Solderability:235±5℃, 5±0.5S 2.Heat resistance:260±5℃,10±1S restoration of 1 hour	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	FC-84 FLUOROCARBON,BUBBLE MACHINE	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、 S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、 Y、 Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、 S&A 250B	Enable Crystal 50G(490m/s ²) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75CM HIGH,3 TIMES ON HARD BOARD	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr; Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP &HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM. STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:40℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9.AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:40℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C5023

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